

ELECTRICAL CHARACTERISTICS ($T_j = 25\text{ }^\circ\text{C}$)

| Symbol | Item | Conditions | Min. | Typ. | Max. | Units | |
|-----------------|---|---|------|------|-------|--------------------|---|
| I_{CES} | Collector cutoff current | $V_{CE}=V_{CES}, V_{GE}=0V$ | — | — | 1 | mA | |
| $V_{GE(th)}$ | Gate-emitter threshold voltage | $I_C=20mA, V_{CE}=10V$ | 6 | 7 | 8 | V | |
| I_{GES} | Gate leakage current | $V_{GE}=V_{GES}, V_{CE}=0V$ | — | — | 0.5 | μA | |
| $V_{CE(sat)}$ | Collector to emitter saturation voltage | $T_j = 25\text{ }^\circ\text{C}$ $I_C = 200A$ | — | 1.8 | 2.5 | V | |
| | | $T_j = 125\text{ }^\circ\text{C}$ $V_{GE} = 15V$ | — | 2.0 | — | | |
| C_{ies} | Input capacitance | $V_{CE}=10V$ | — | — | 47 | nF | |
| C_{oes} | Output capacitance | $V_{GE}=0V$ | — | — | 4 | | |
| C_{res} | Reverse transfer capacitance | | — | — | 0.9 | | |
| Q_G | Total gate charge | $V_{CC}=600V, I_C=200A, V_{GE}=15V$ | — | 1350 | — | nC | |
| $t_{d(on)}$ | Turn-on delay time | $V_{CC}=600V, I_C=200A$ | — | — | 500 | ns | A |
| t_r | Turn-on rise time | $V_{GE1}=V_{GE2}=15V$ | — | — | 150 | | |
| $t_{d(off)}$ | Turn-off delay time | $R_G=1.6\Omega$, Inductive load | — | — | 600 | | |
| t_f | Turn-off fall time | switching operation | — | — | 350 | | |
| t_{rr} ① | Reverse recovery time | $I_E=200A$ | — | — | 250 | ns | |
| Q_{rr} ① | Reverse recovery charge | | — | 7.5 | — | μC | A |
| V_{EC} ① | Emitter-collector voltage | $I_E=200A, V_{GE}=0V$ | — | — | 3.2 | V | |
| $R_{th(j-c)Q}$ | Thermal resistance | IGBT part (1/2 module) *1 | — | — | 0.11 | $^\circ\text{C/W}$ | |
| $R_{th(j-c)R}$ | | FWDi part(1/2 module) *1 | — | — | 0.19 | | |
| $R_{th(c-f)}$ | Contact thermal resistance | Case to fin,Thermal compound Applied (1/2module) *2 | — | 0.04 | — | | |
| $R_{th(j-c')Q}$ | Thermal resistance | IGBT part (1/2 module) *3 | — | — | 0.066 | | B |
| R_G | External gate resistance | | 1.6 | — | 16 | Ω | |

*1: T_c measured point is shown in page OUTLINE DRAWING.

*2: Typical value is measured by using Shin-etsu Silicone "G-746".

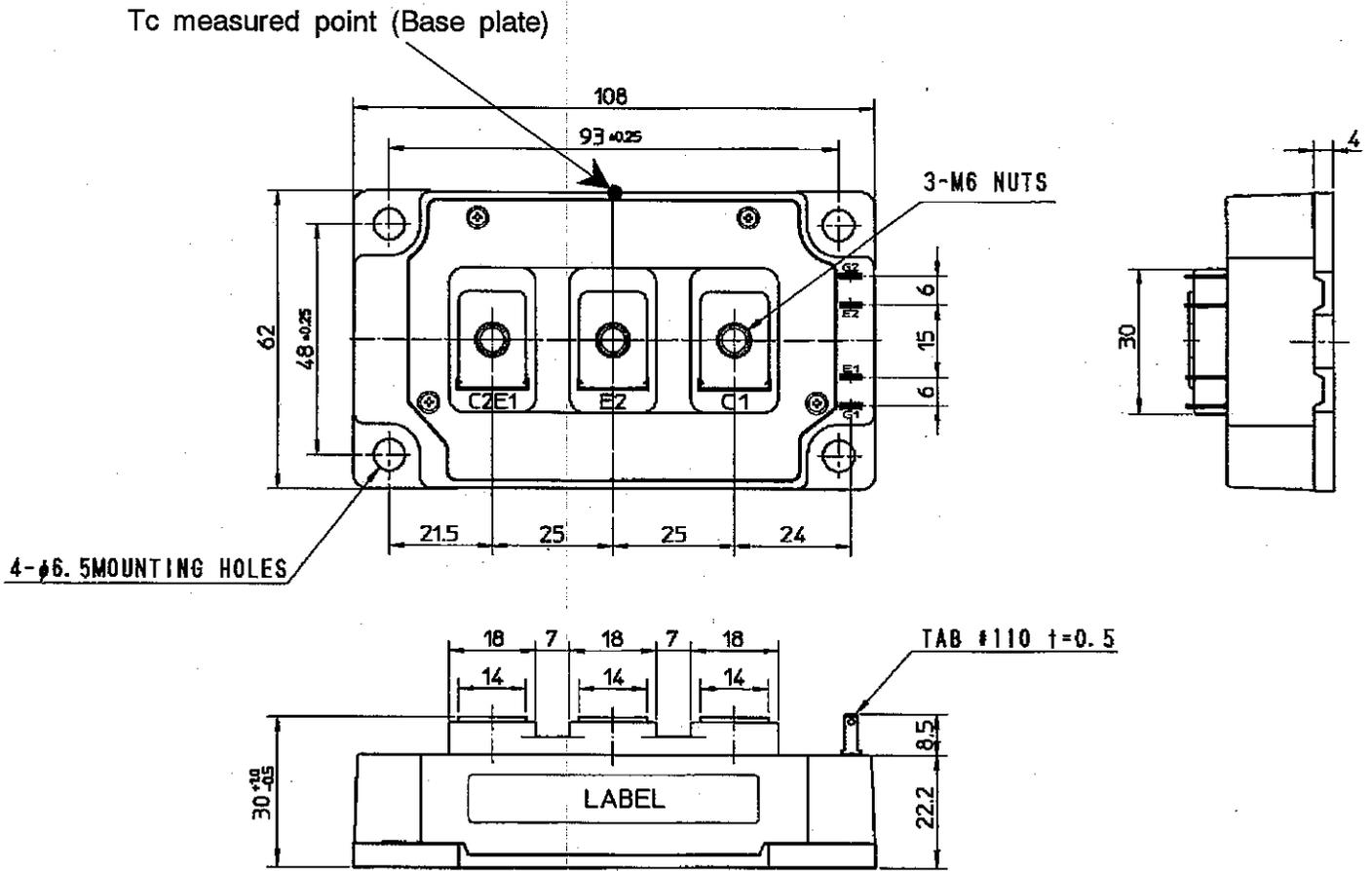
*3: T_c measured point is just under the chips.

If you use this value, $R_{th(f-a)}$ should be measured just under the chips.

- ① $I_E, V_{EC}, t_{rr}, Q_{rr}$ & die/dt represent characteristics of the anti-parallel, emitter to collector free-wheel diode (FWDi).
- ② Pulse width and repetition rate should be such that the device junction temp. (T_j) dose not exceed T_{jmax} rating.
- ③ Junction temperature (T_j) should not increase beyond 150°C .
- ④ Pulse width and repetition rate should be such as to cause neglible temperature rise.

OUTLINE DRAWING

Dimensions in mm



CIRCUIT DIAGRAM

